



FDP75N08A 75V N-Channel MOSFET

Features

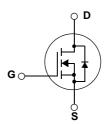
- 75A, 75V, $R_{DS(on)} = 0.011\Omega @V_{GS} = 10 V$ Low gate charge (typical 145nC)
- Low Crss (typical 86pF)
- · Fast switching
- Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies, active power factor correction, electronic lamp ballast based on half bridge topology.





Absolute Maximum Ratings

Symbol	Parameter		FDP75N08A	Units	
V _{DSS}	Drain-Source Voltage		75	V	
I _D	Drain Current - Continuous (T _C = 25°C)		75	A	
	- Continuous (T _C = 100°C)		47	A	
I _{DM}	Drain Current - Pulsed	(Note 1)	300	А	
V _{GSS}	Gate-Source Voltage		± 20	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1738	mJ	
I _{AR}	Avalanche Current	(Note 1)	75	А	
E _{AR}	Repetitive Avalanche Energy (Note 1)		13.7	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns	
P _D	Power Dissipation (T _C = 25°C)		137	W	
- Derate above 25°C			1.09	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	FDP75N08A	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.91	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP75N08A	FDP75N08A	TO-220		-	50

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	teristics					-11
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	75			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25°C		0.6		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 75 V, V _{GS} = 0 V			1	μА
		V _{DS} = 60 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Charact	eristics					•
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 37.5 A		9.4	11	mΩ
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 37.5 A (Note 4)		15		S
Dynamic Cl	haracteristics		1			1
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		3437	4468	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		738	959	pF
C _{rss}	Reverse Transfer Capacitance			86	129	pF
Switching C	Characteristics		I.			1
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 37.5 \text{ V}, I_D = 75\text{A},$		43	95	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		212	434	ns
t _{d(off)}	Turn-Off Delay Time			273	556	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		147	303	ns
Qg	Total Gate Charge	V _{DS} = 60 V, I _D = 75A,		80	104	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		20		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		24		nC
Drain-Sour	ce Diode Characteristics and Maximum Ratings			1	I.	
I _S	Maximum Continuous Drain-Source Diode Forward Current				75	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				300	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 75 \text{ A}$			1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 75 \text{ A},$		62		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		145		nC

NOTES:

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 206 μ H, I_{AS} =75A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 3. $I_{SD} \le 75 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

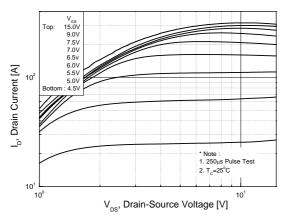


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 2. Transfer Characteristics

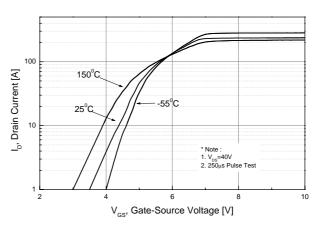
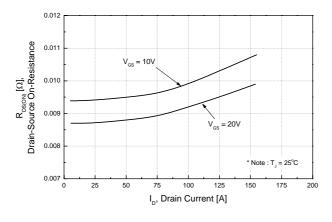


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



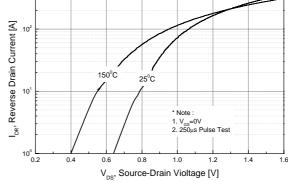


Figure 5. Capacitance Characteristics

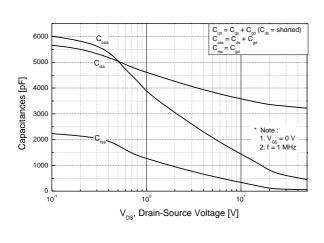
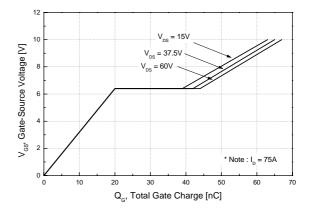


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

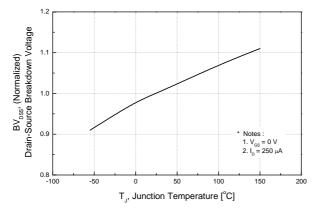


Figure 8. On-Resistance Variation vs. Temperature

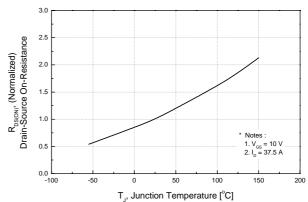


Figure 9. Maximum Safe Operating Area

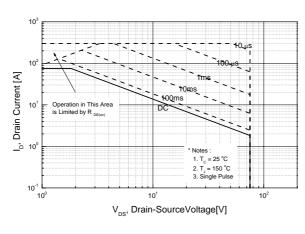


Figure 10. Maximum Drain Current vs. Case Temperature

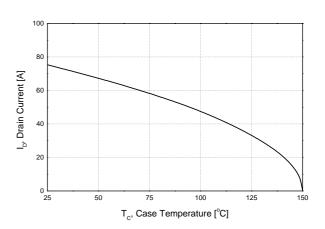
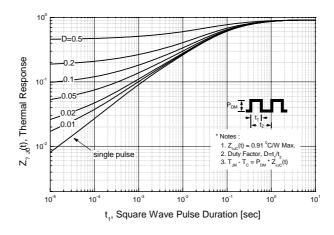
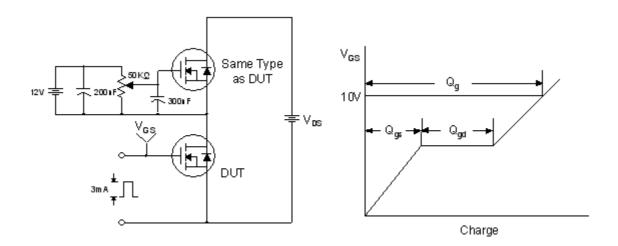


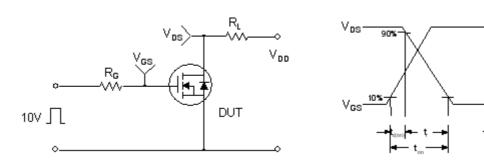
Figure 11. Transient Thermal Response Curve



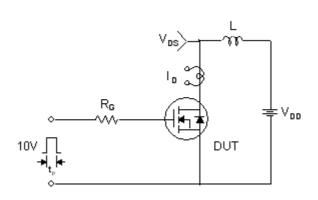
Gate Charge Test Circuit & Waveform

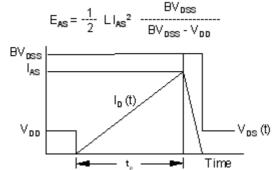


Resistive Switching Test Circuit & Waveforms

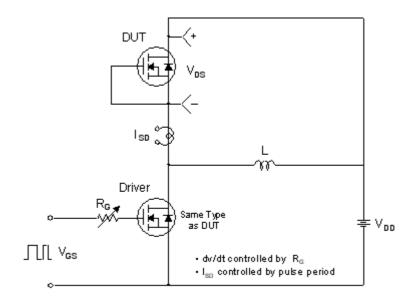


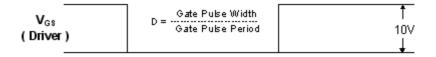
Unclamped Inductive Switching Test Circuit & Waveforms

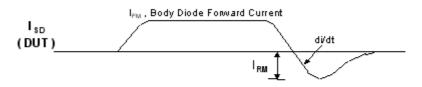


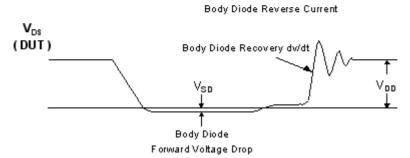


Peak Diode Recovery dv/dt Test Circuit & Waveforms



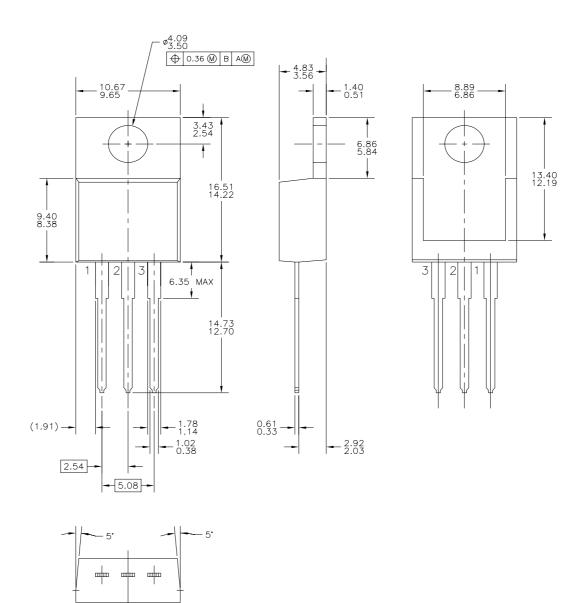






Mechanical Dimensions

TO-220



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Dimensions in Millimeters

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